

On multiple fault detection in combinational logic circuits

Birger, Alexander BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 225-228

Simulation and automated test development system for digital devices

Birger, Alexander BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 293-295